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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: OKUBO et al.

Appln. No.: 10/544,178

Filing Date: April 24, 2006

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Page 1 of 1

Examiner: MOORE, W.

Group Art Unit: 2826

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
/W.M./	AR 5,770,861	06-23-1998	Hirose et al.			
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
					Enclosed	No
OR						
PR						
QR						
RR						
SR						
TR						

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.):

/W.M./	UR	Inkon B J et al.: "Subsurface nanoindentation deformation of Cu-Al multilayers mapped in 3D by focused ion beam microscopy," Journal of Microscopy, vol. 201, pt. 2, February 2001, pp. 256-269			X
/W.M./	VR	Dunn D N et al.: "Reconstruction of three-dimensional chemistry and geometry using focused ion beam microscopy," Applied Science Letters, vol. 75, number 21, November 22, 1999, pages 3414-3416			X
/W.M./	WR	Sakamoto T. et al.: "Development of an ion and electron dual focused beam apparatus for three-dimensional microanalysis," Japanese Journal of Applied Physics, vol. 37, no. 4A, April 1998, pages 2051-2056			X
/W.M./	XR	Supplementary European Search Report for European Application Number EP 03 75 6661 dated December 17, 2009			X

Examiner /Whitney Moore/

Date Considered: 01/15/2010

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.